

BUL903EDFP

HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- INTEGRATED ANTISATURATION AND PROTECTION NETWORK
- INTEGRATED ANTIPARALLEL COLLECTOR EMITTER DIODE
- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED
- ARCING TEST SELF PROTECTED
- FULLY INSULATED PACKAGE (U.L. COMPLIANT) FOR EASY MOUNTING

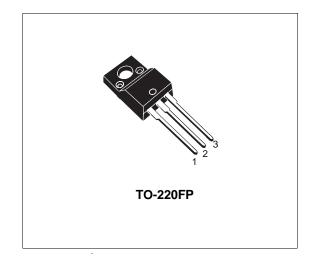
APPLICATIONS

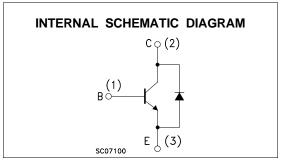
 FOUR LAMP ELECTRONIC BALLAST FOR 120 V MAINS IN PUSH-PULL CONFIGURATION

DESCRIPTION

The BUL903EDFP is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and high voltage capability.

The device has been designed to operate without baker clamp and transil protection. This enables saving from 2 up to 10 components in the application.





Symbol	Parameter	Value	Unit
V _{CES}	Collector-Emitter Voltage (V _{BE} = 0)	900	V
V _{CEO}	Collector-Emitter Voltage $(I_B = 0)$	400	V
V _{EBO}	Emitter-Base Voltage $(I_C = 0)$	7	V
Ι _C	Collector Current	5	А
Ісм	Collector Peak Current (tp <5 ms)	8	А
IB	Base Current	2	А
I _{BM}	Base Peak Current (t _p <5 ms)	4	А
P _{tot}	Total Dissipation at Tc = 25 °C	35	W
Visol	Insulation Withstand Voltage (RMS) from All Three Leads to Exernal Heatsink	1500	V
T _{stg}	Storage Temperature	-65 to 150	°C
Ti	Max. Operating Junction Temperature	150	°C

ABSOLUTE MAXIMUM RATINGS

September 2003

THERMAL DATA

R _{thj-case}	Thermal Resistance Junction-Case	Max	3.57	°C/W
R _{thj} -amb	Thermal Resistance Junction-Ambient	Max	62.5	°C/W

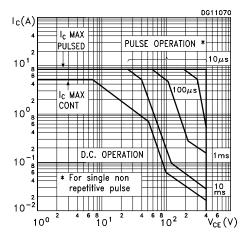
ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

Symbol	Parameter	Test	Conditions	Min.	Тур.	Max.	Unit
ICES	Collector Cut-off Current (V _{BE} = 0)	V _{CE} = 900 V				100	μA
I _{EBO}	Emitter Cut-off Current (I _C = 0)	V _{EB} = 7 V				100	μA
$V_{(BR)CES}$	Collector-Emitter Breakdown Voltage (V _{BE} = 0)	I _C = 100 μA		900			V
$V_{CEO(sus)^*}$	Collector-Emitter Sustaining Voltage (I _B = 0)	I _C = 10 mA	L = 25 mH	400			V
VCE(sat)*	Collector-Emitter Saturation Voltage	Ic = 0.5 A I _C = 1 A I _C = 2 A	I _B = 50 mA I _B = 0.15 A I _B = 0.4 A			0.5 1 1.5	V V V
$V_{BE(sat)^*}$	Base-Emitter Saturation Voltage	$I_{C} = 0.5 A$ $I_{C} = 1 A$ $I_{C} = 2 A$	I _B = 50 mA I _B = 0.15 A I _B = 0.4 A			1 1.1 1.2	V V V
h _{FE} *	DC Current Gain		V _{CE} = 5 V V _{CE} = 5 V V _{CE} = 5 V V _{CE} = 5 V	20 40 28 8		70 60 16	
t _d tr ts t _f	RESISTIVE LOAD Delay Time Rise Time Storage Time Fall Time	$V_{CC} = 125 V$ $I_{B1} = 50 mA$ $t_p = 300 \mu s$ (see figure 1)	I _C = 0.7 A I _{B2} = 0.4 A			0.2 1 0.8 0.25	μs μs μs μs
E _{ar}	Repetitive Avalanche Energy	$V_{CC} = 50V$ $V_{BE} = -5 V$ (see figure 2)	C = 1.8 nF L = 2 mH	6			mJ
VF	Parallel Diode Forward Voltage	I _F = 2 A				1.2	V

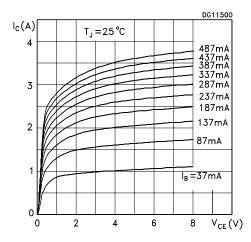
* Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

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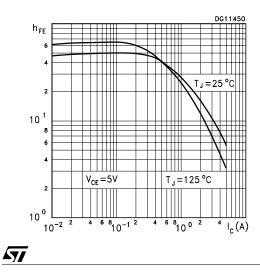
Safe Operating Area



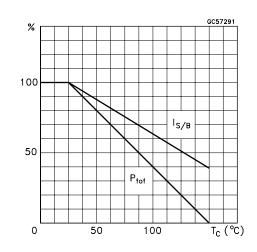
Output Characteristics



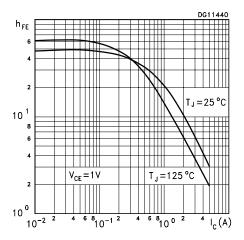
DC Current Gain



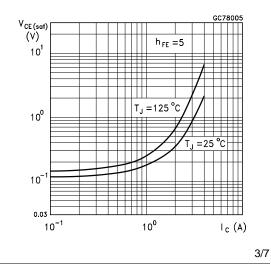
Derating Curve



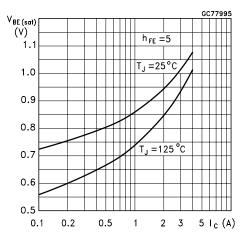
DC Current Gain



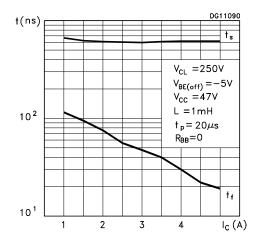




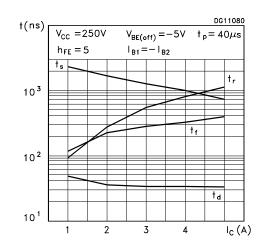
Base Emitter Saturation Voltage



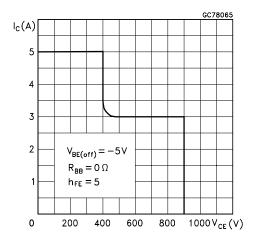
Switching Times Inductive Load



Switching Times Resistive Load







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Figure 1: Resistive Load Switching Test Circuit

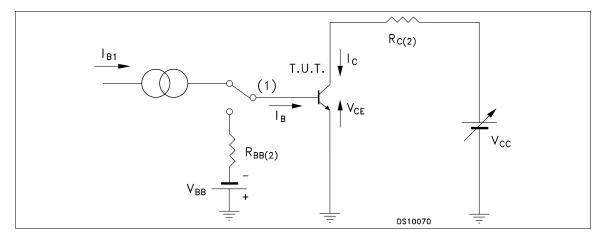
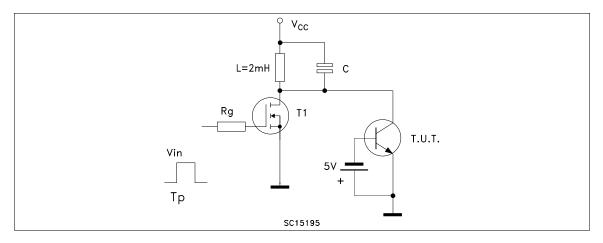
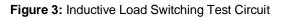
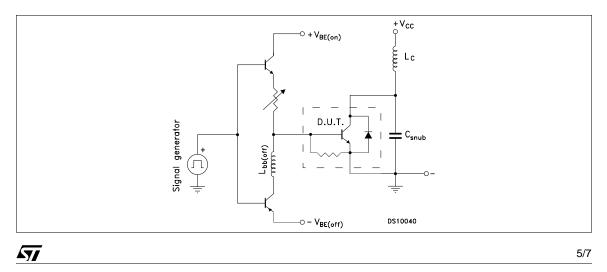


Figure 2 : Energy Rating Test Circuit



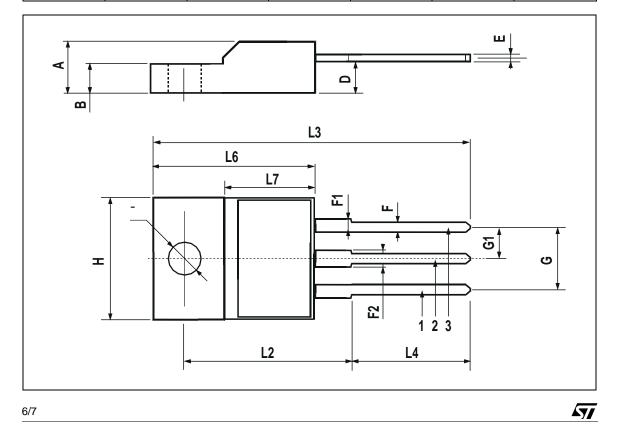




BUL903EDFP

DIM.	mm			inch			
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	4.4		4.6	0.173		0.181	
В	2.5		2.7	0.098		0.106	
D	2.5		2.75	0.098		0.108	
E	0.45		0.7	0.017		0.027	
F	0.75		1	0.030		0.039	
F1	1.15		1.7	0.045		0.067	
F2	1.15		1.7	0.045		0.067	
G	4.95		5.2	0.195		0.204	
G1	2.4		2.7	0.094		0.106	
Н	10		10.4	0.393		0.409	
L2		16			0.630		
L3	28.6		30.6	1.126		1.204	
L4	9.8		10.6	0.385		0.417	
L6	15.9		16.4	0.626		0.645	
L7	9		9.3	0.354		0.366	
Ø	3		3.2	0.118		0.126	





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